

**Elucidating the assembly of Nanoparticle Organic Hybrid Materials  
(NOHMs) near the electrode interface with varying potential using Neutron  
Reflectivity**

Md Ashraful Haque<sup>a</sup>, Sara T. Hamilton<sup>c,d</sup>, Tony G. Feric<sup>b,d</sup>, Ah-Hyung Alissa Park<sup>b,c,d</sup>,

Mark D. Dadmun<sup>a\*</sup>

<sup>a</sup>Department of Chemistry

The University of Tennessee, Knoxville, TN, 37996, USA

<sup>b</sup>Department of Chemical Engineering,

Columbia University, New York, NY 10027, USA

<sup>c</sup>Department of Earth and Environmental Engineering,

Columbia University, New York, NY 10027, USA

<sup>d</sup>Lenfest Center for Sustainable Energy, The Earth Institute, Columbia University

**Supporting Information:**

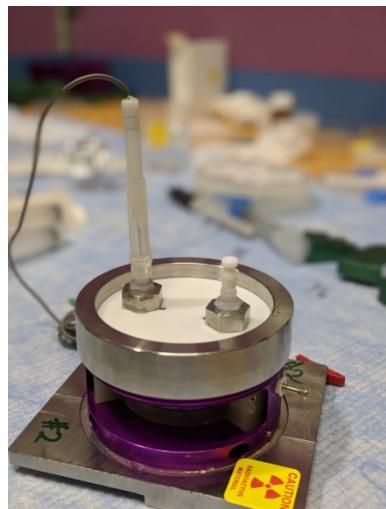


Figure S1 A picture of the cell used for neutron reflectivity experiments.

<b>Component</b>	<b>SLD (<math>10^{-6} \text{ \AA}^{-2}</math>)</b>	<b>Additional Relevant Parameters</b>
Si	2.07	
Au	4.63	
Cr	3.03	
SiO	2.89	
HPE polymer	0.52	MW = 2,000 g/mol, Rg ~ 15 Å
SiO <sub>2</sub> Nanoparticle	4.20	Diameter = 45 Å
D <sub>2</sub> O	6.35	
K	0.49	
Zn	3.73	

Table S1. SLD of the components calculated using neutron activation calculator.

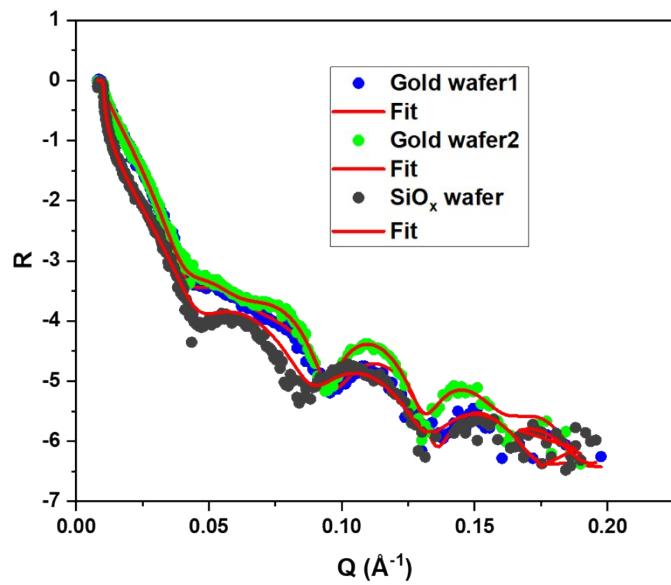


Figure S2 Neutron reflectivity profiles of Au (green and blue circles) and SiO<sub>x</sub> wafers (black circles) with fit (red line)

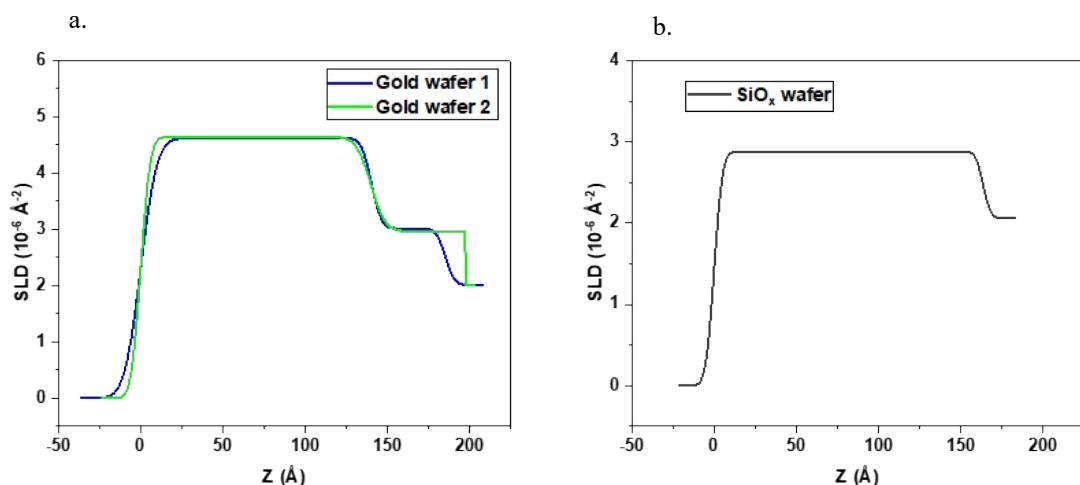


Figure S3 SLD profile of Au (a) and SiO<sub>x</sub> (b) wafers obtained from reflectivity fit of the Au and SiO<sub>x</sub> wafers.

Table S2 Density profile parameters of Au and SiO<sub>x</sub> wafers obtained from the reflectivity fit of the Au and wafers.

<b>Sample</b>	<b>Parameters</b>	<b>Si</b>	<b>SiO<sub>x</sub></b>	<b>Cr</b>	<b>Au</b>	<b>SiO<sub>x</sub></b>
	SLD ( $10^{-6}$ Å <sup>-2</sup> ) ± error	2.07	2.89			
<b>SiO<sub>x</sub> Wafer in air</b>	Z (Å) ± error	-	143 ± 0.50			
	R(Å) ± error	1.5	4.88 ± 0.20			
	SLD ( $10^{-6}$ Å <sup>-2</sup> ) ± error	2.07	-	3.03	4.63	
<b>Au Wafer in air</b>	Z (Å) ± error	-	-	46.4 ± 0.12	140 ± 1	
	R(Å) ± error	4.0 ± 0.1	-	7.96 ± 0.01	4.94 ± 0.07	
	SLD ( $10^{-6}$ Å <sup>-2</sup> ) ± error	2.07	-	3.03	4.63	
<b>Au Wafer in air</b>	Z (Å) ± error	-	-	56.6 ± 0.18	140 ± 1	
	R(Å) ± error	1.00 ± 0.01	-	5.36 ± 0.30	7.24 0.38	

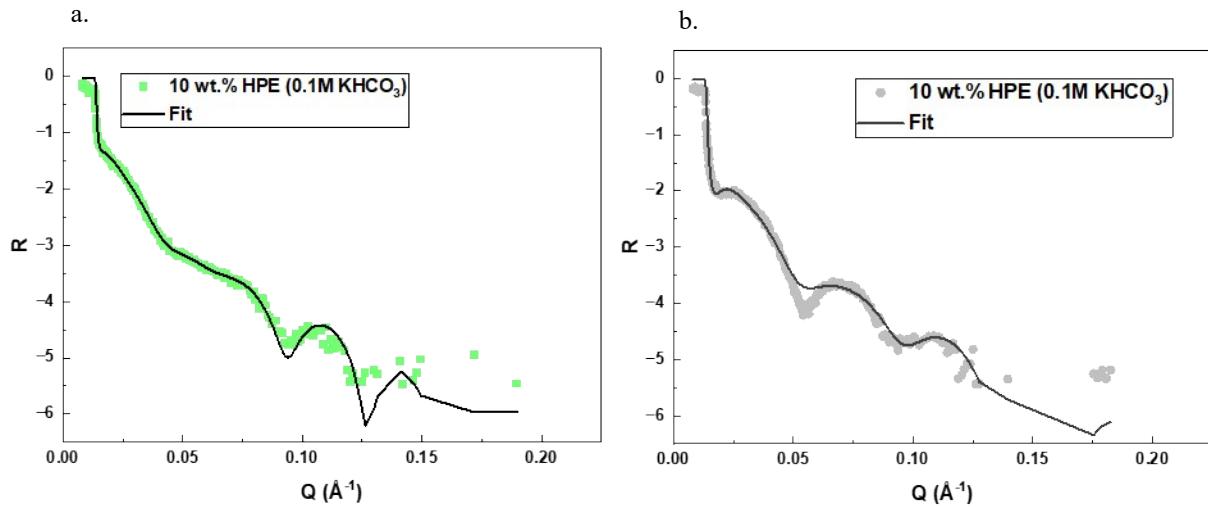


Figure S4 Neutron reflectivity profiles (circles) and fit (line) of 10 wt.% HPE in  $\text{D}_2\text{O}$  in presence of 0.1 M  $\text{KHCO}_3$  salt near Au surface (a) and  $\text{SiO}_x$  surface (b).

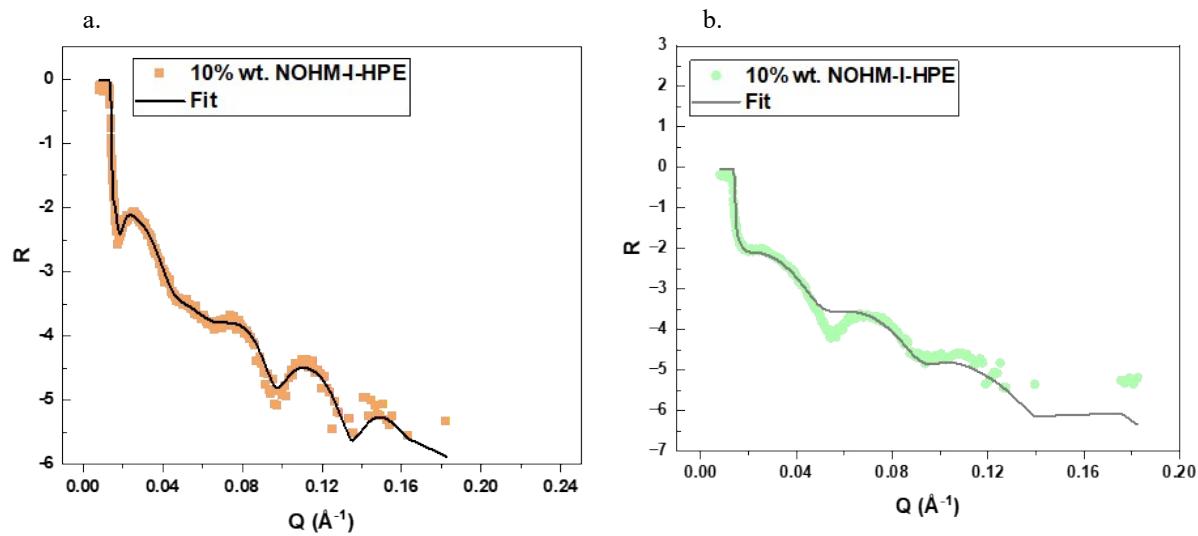


Figure S5. Neutron reflectivity profiles (circles) and fit (black line) of 10 wt.% NOHM-I-HPE in  $\text{D}_2\text{O}$  near Au surface (a) and  $\text{SiO}_x$  surface (b).

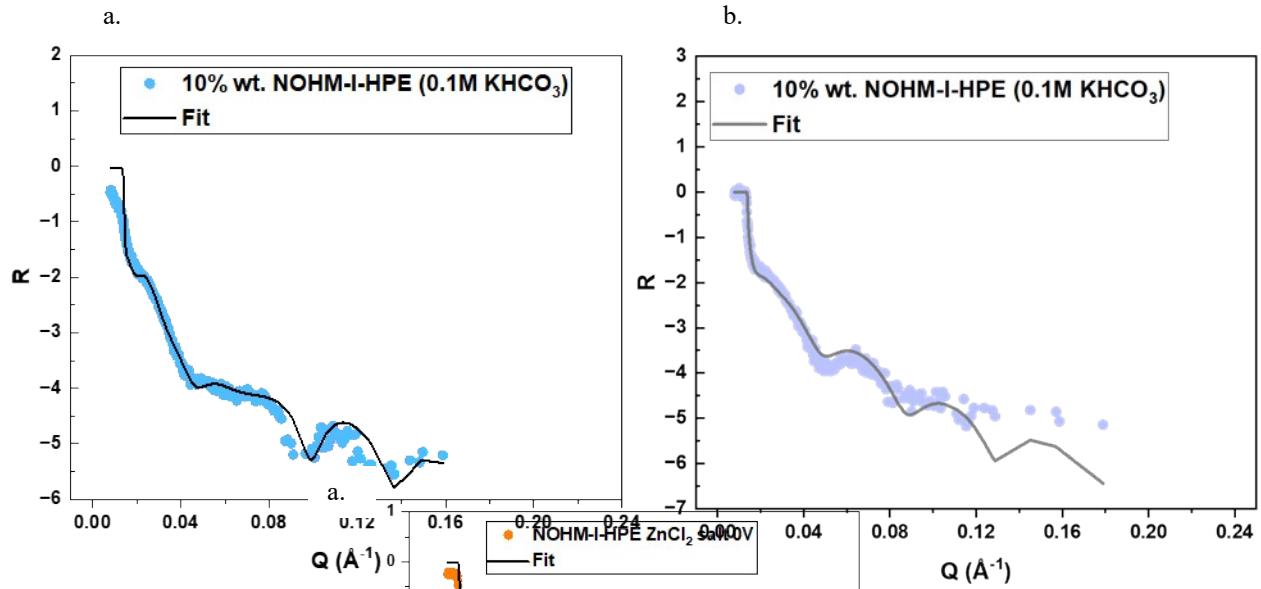


Figure S6 Neutron reflectivity profiles (circles) and fit (lines) of 10 wt.% NOHM-I-HPE in  $\text{D}_2\text{O}$  in presence of 0.1M  $\text{KHCO}_3$  salt near Au surface (a) and  $\text{SiO}_x$  surface (b).

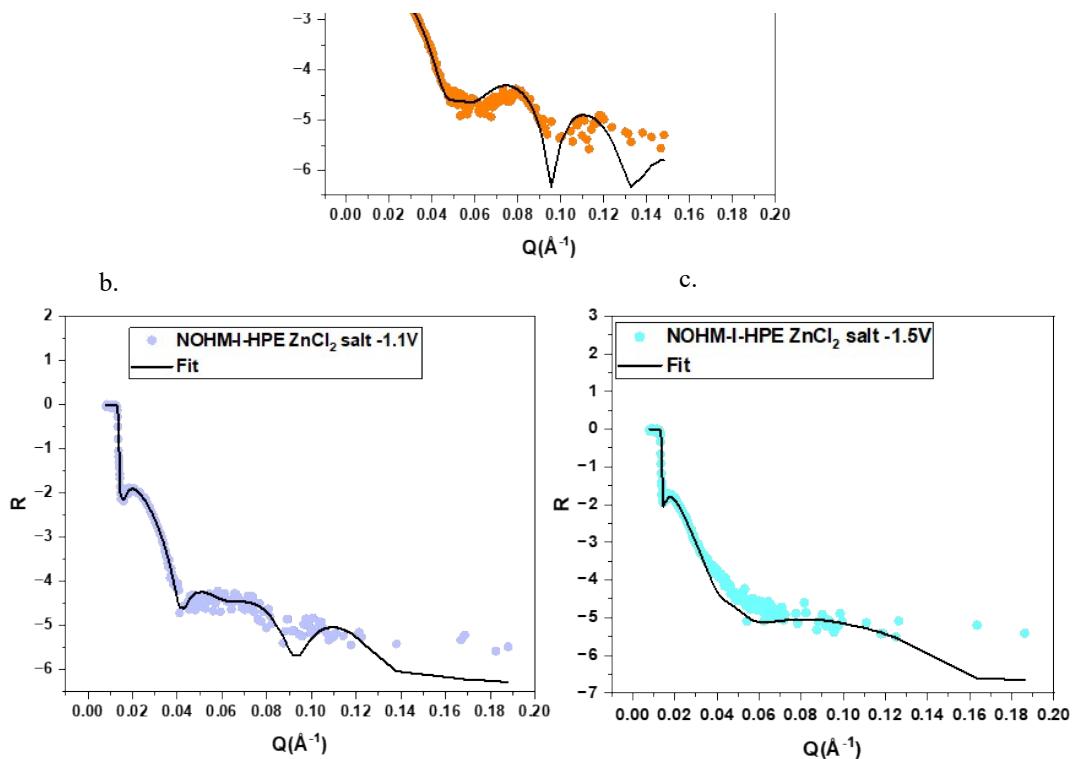


Figure S7 Neutron reflectivity profile (circle) and fit (line) of 10 wt.% NOHM-I-HPE in  $\text{D}_2\text{O}$  in presence of  $\text{ZnCl}_2$  salt near Au surface at different potentials; 0V (a) -1.1V (b), -1.5V (c).

